What is claimed is:

1. A method of detecting defect signals includes:

   receiving a reference signal when recording a data pit;

   sampling the reference signal and holding a DC value with respect to a sampling point of the reference signal; and

   determining if said DC value is within a default range, and according to the result, setting a defect flag signal, which default logic state is at a first logic state;

   wherein the sampling point is a static region of the reference signal.

2. The method of claim 1, wherein the reference signal is an intensity signal of a reflective laser beam.

3. The method of claim 1, if the defect flag signal is at the first logic state, when the DC value according to the sampling point is not within the default range, thus changing the defect flag signal at a second logic state.

4. The method of claim 1, if the defect flag signal is at the first logic state, when the DC value according to the sampling point is within the default range, thus keeping the defect flag signal at the first logic state.

5. The method of claim 1, if the defect flag signal is at a second logic state, when the DC value according to the sampling point is not within the default range, thus keeping the defect flag signal at the second logic state.

6. The method of claim 1, if the defect flag signal is at a second logic state, when the DC value according to the sampling point is within the default range, thus changing the defect flag signal at the first logic state.

7. The method of claim 1, wherein the method could be applied to a recording and reproducing system.

8. The method of claim 7, wherein the recording and reproducing system is selected from: a Cd-RW, a DVD+RW, a DVD-RW, a CD-MRW, DVD+MRW.

9. An apparatus of detecting defect signals includes:

a photodetector circuit, detecting a intensity of a reflected laser beam and generating a reflected signal when recording a data into a disk;

a sample/hold circuit, coupling to the photodetector circuit, sampling the reflected signal and holding a DC value with respect to a sampling point;

a comparator, coupling to the sample/hold circuit, comparing the DC value with a default range; and

a defect flag generating circuit, coupling to the comparator, generating a defect flag signal, which default logic state is at a first logic state, and changing its logic state according to the comparing results.

wherein the sampling point is a static region of the reflected signal.

10. The method of claim 9, if the defect flag signal is at the first logic state, when the DC value according to the sampling point is not within the default range, changing the defect flag signal at a second logic state.

11. The method of claim 9, if the defect flag signal is at the first logic state, when the DC value according to the sampling point is within the default range, keeping the defect flag signal at the first logic state.

12. The method of claim 9, if the defect flag signal is at a second logic state, when the DC value according to the sampling point is not within the default range, keeping the defect flag signal at the second logic state.

13. The method of claim 9, if the defect flag signal is at a second logic state, when the DC value according to the sampling point is within the default range, changing the defect flag signal at the first logic state.

14. The method of claim 9, wherein the apparatus could be applied to a recording and reproducing system.

15. The method of claim 14, wherein the recording and reproducing system is selected

from: a CD-RW, a DVD+RW, a DVD-RW, a CD-MRW, DVD+MRW.